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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): ANATOLY FABRIKANT, GUOHENG ZHAO, DANIEL C. WACK and MEHRDAD NIKOONAHAD
Assignee: KLA-TENCOR TECHNOLOGIES CORPORATION

Title: IMPROVED SYSTEM FOR SCATTEROMETRIC MEASUREMENTS AND APPLICATIONS

Serial No.: 09/671,715 Filing Date: September 27, 2000

Examiner: Unknown Group Art Unit: 2877

Docket No.: M-10699 US

San Jose, California
April 24, 2001

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT

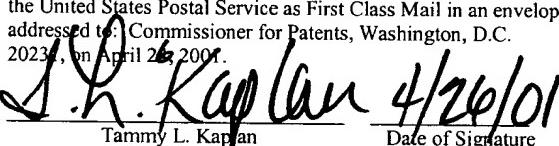
Dear Sir:

Applicants wish to call the enclosed documents to the attention of the Examiner. A PTO form 1449 listing these documents is enclosed.

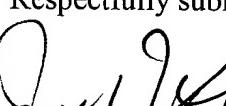
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I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on April 26, 2001.


Tammy L. Kaplan 4/26/01
Date of Signature

Respectfully submitted,


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U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Serial No.
		M-10699 US	09/671,715
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use several sheets if necessary)</i>		Applicant(s)	
		ANATOLY FABRIKANT ET AL.	
		Filing Date	Group
		September 27, 2000	2877

U.S. Patent Documents

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

Foreign Patent Documents

		Document	Date	Country	Class	Subclass	Yes	No	Translation
	AL	WO99/45340	9/10/99	International			X		
	AM								
	AN								
	AO								
	AP								

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	"Multilayer modal method for diffraction gratings of arbitrary profile, depth, and permittivity," L. Li, <i>J. Opt. Soc. Am. A.</i> , Vol. 10, No. 12, December 1993, pp. 2581-2591
	AR	"Rigorous coupled-wave analysis of planar-grating diffraction," M.G. Moharam et al., <i>J. Opt. Soc. Am.</i> , Vol. 71, No. 7, July 1981, pp. 811-818
	AS	"Coupled-Wave Analysis of Two-Dimensional Dielectric Gratings," M.G. Moharam, <i>SPIE</i> , Vol. 883, <i>Holographic Optics: Design and Applications</i> , 1988, pp. 8-11

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.